

Dual-Component Functionalized Allylated Calix[4]arene-Dibutyltin Diacrylate Blends as Organic-Inorganic Hybrid Resist Compositions for Nanolithography

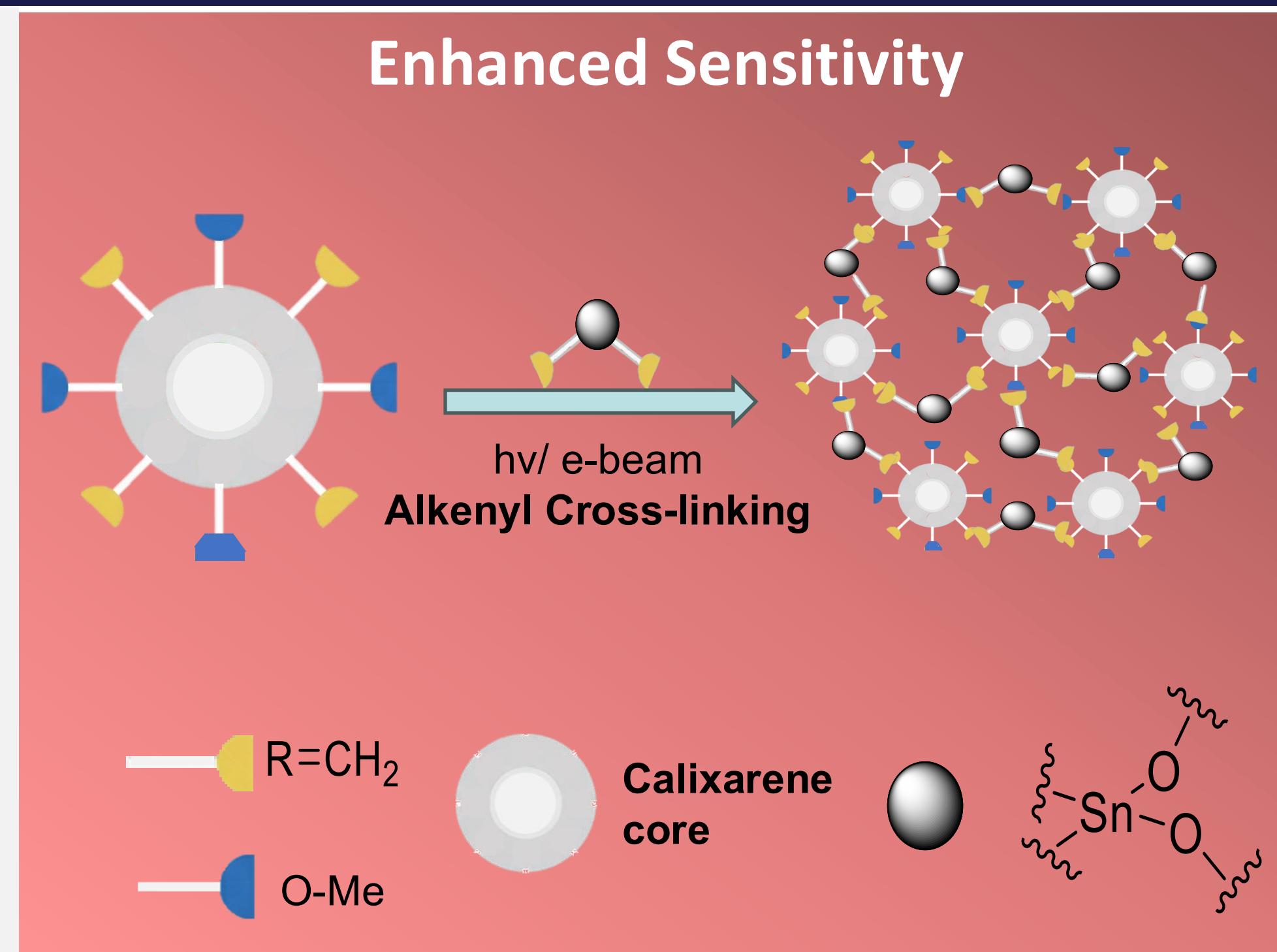
SPIE

Promit Chakraborty^a, Neha Thakur^b, Avik Das^a, Santu Nandi, Manvendra Chauhan^c, Prashant Varma^d, Nilesh Ladani^d, Ambar Shukla^d, Satinder. K. Sharma^c, Subrata Ghosh^a



INTRODUCTION

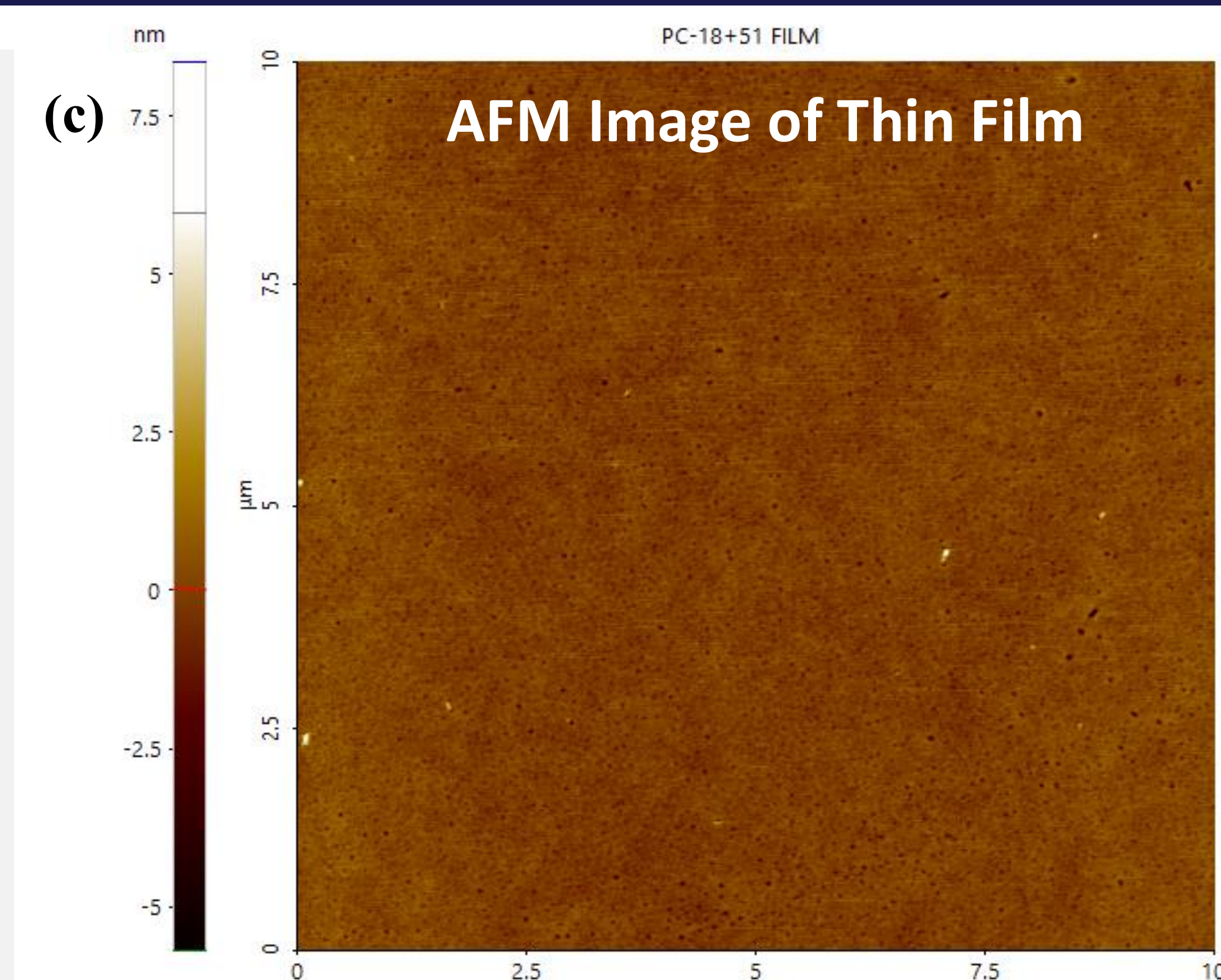
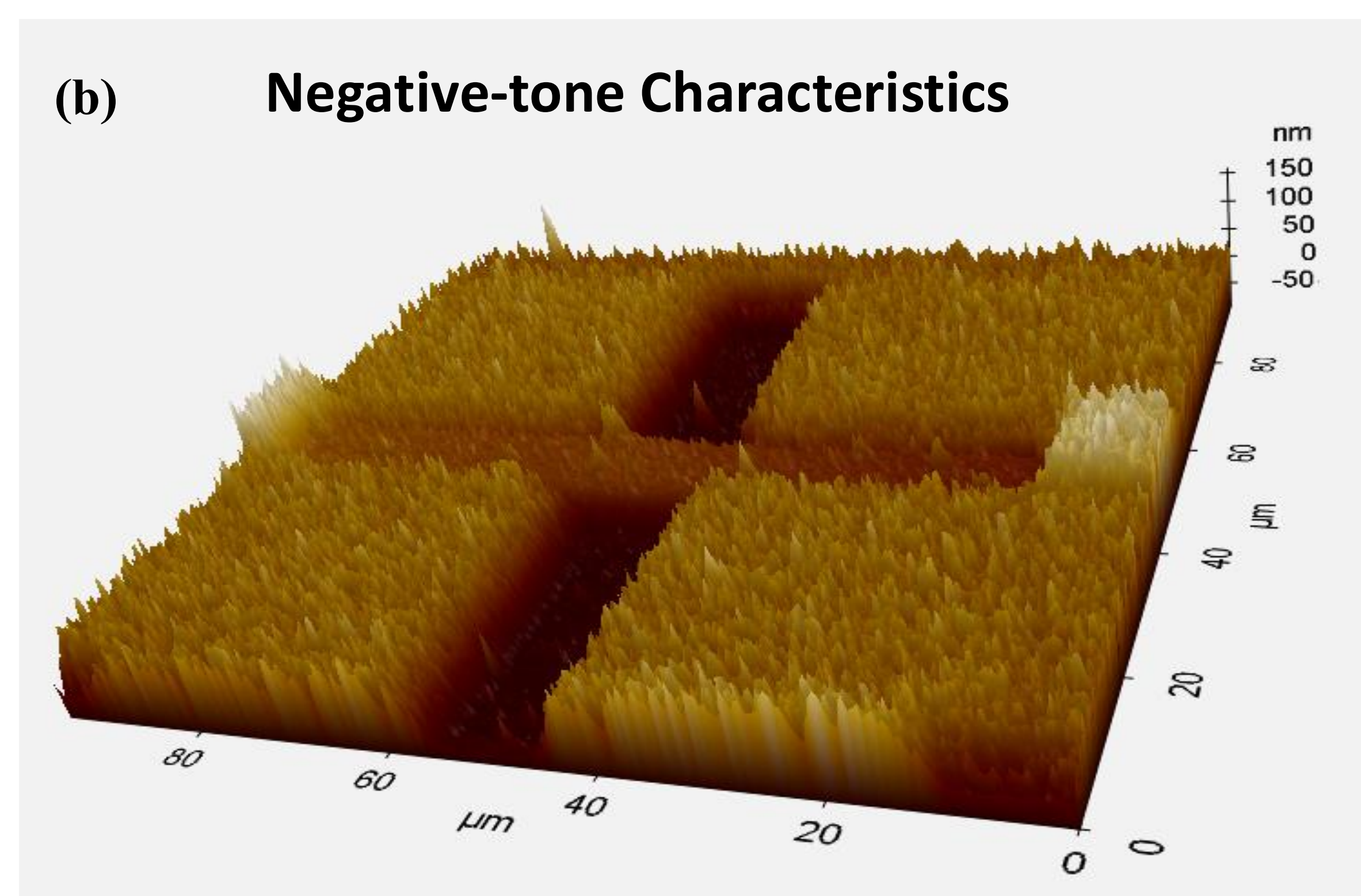
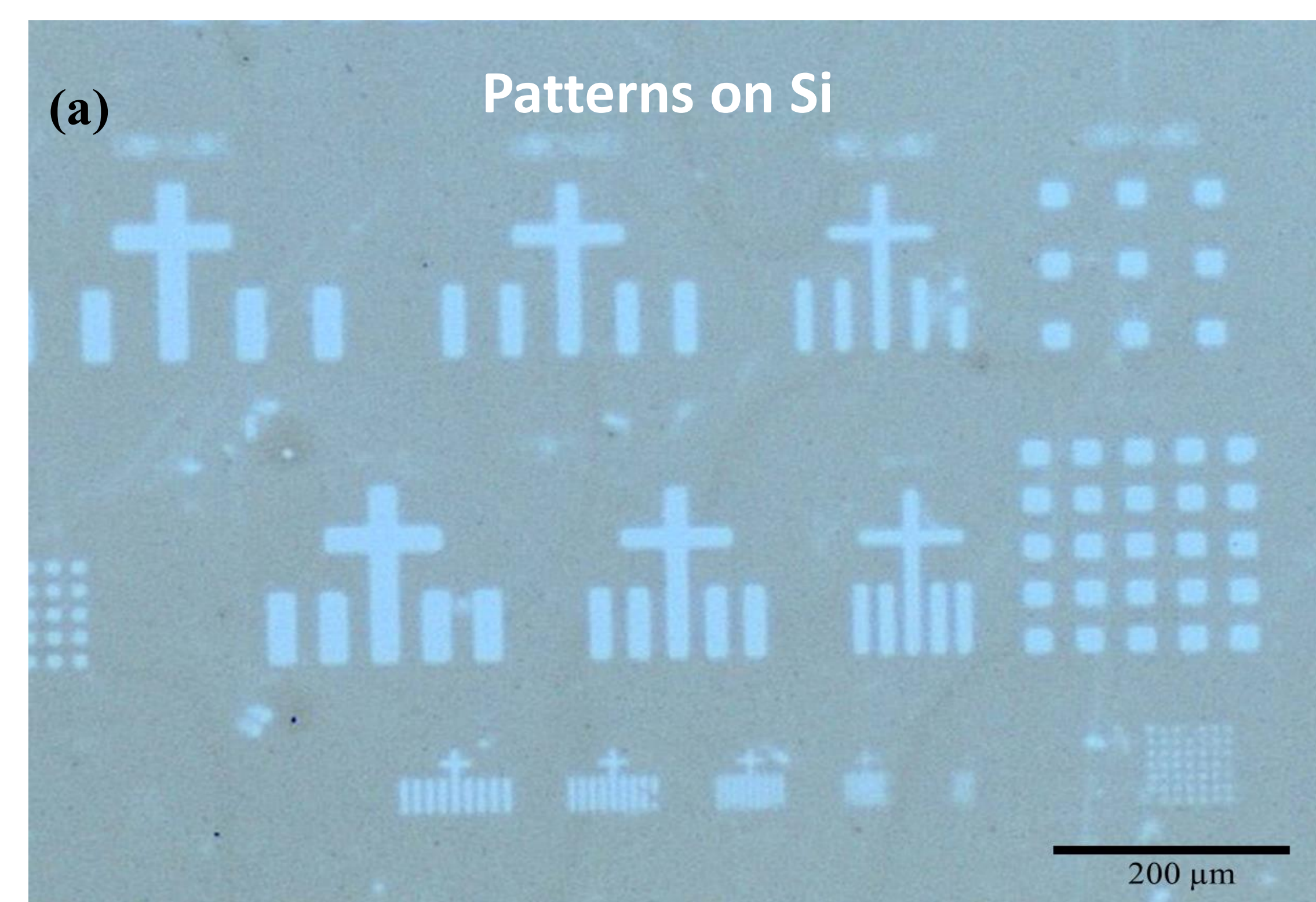
- Conventional organic resists face resolution limits, while inorganic systems suffer other challenges, such as low sensitivity & poor processibility.¹
- Hybrid organic-inorganic systems² offer a promising platform to balance sensitivity, resolution, and thin film stability.
- In this work, we report a functionalised **calixarene-Sn diacrylate integrated resist** designed to enhance absorption and efficient crosslinking.



KEY-RESULTS

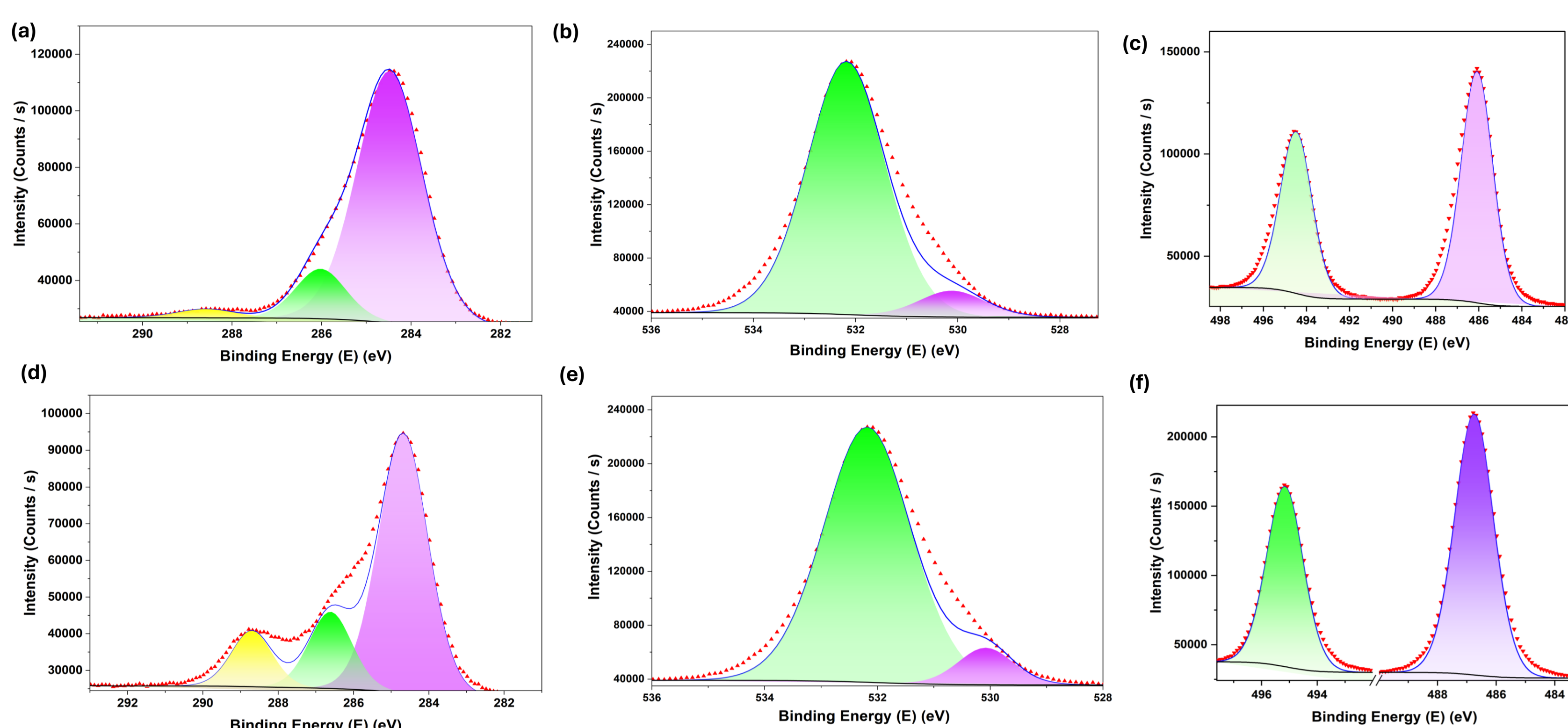
- Demonstrated **good film-forming capability**
- Successful **negative-tone DUV patterning**
- Hybrid Sn-calixarene architecture enables **enhanced sensitivity via crosslinking**
- Patterning sensitivity improvement to a larger extent over analogous systems.³

PHOTOLITHOGRAPHY AND THIN FILM STUDIES



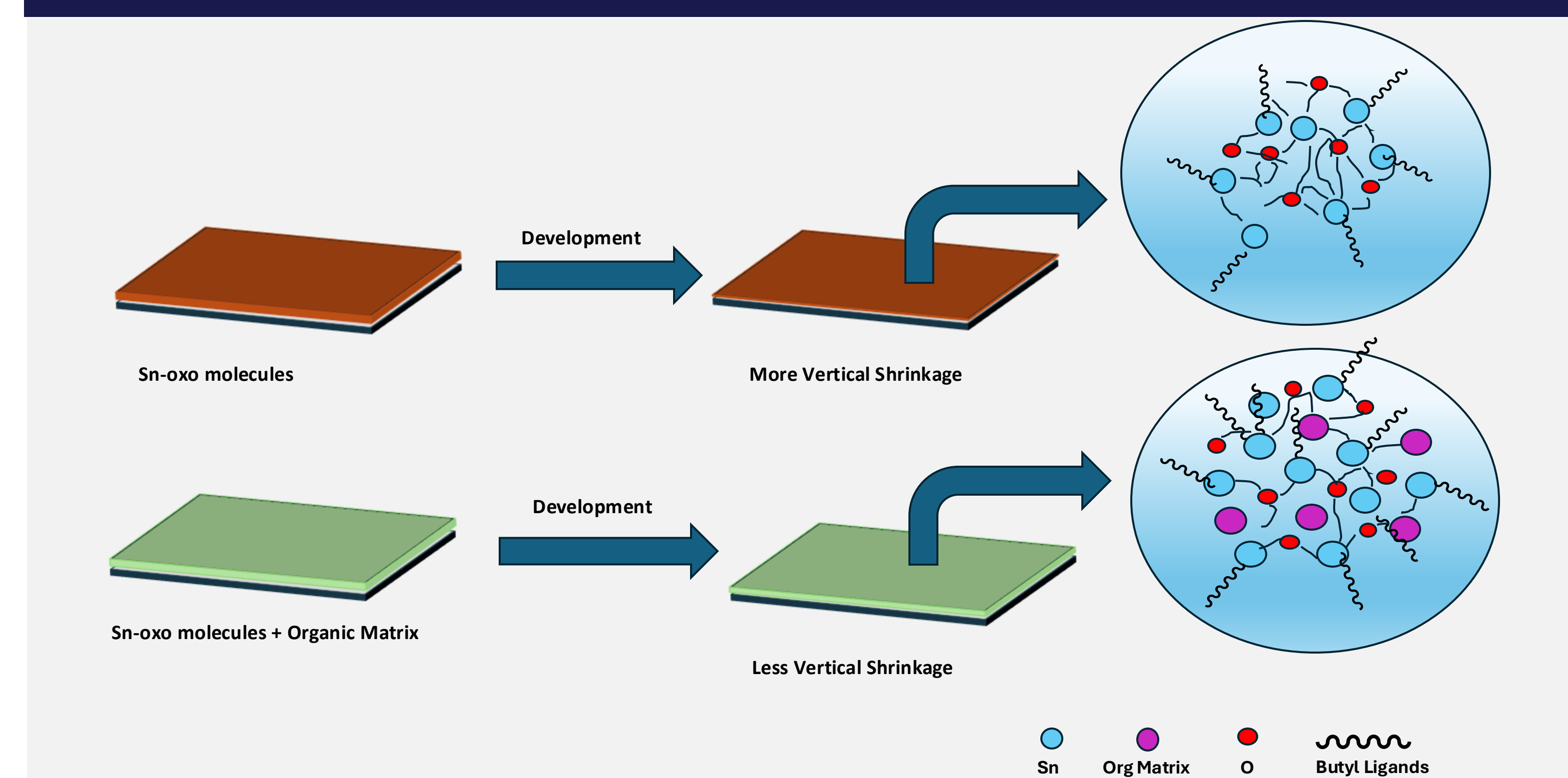
(a) Optical Microscope Image of Micron-sized features (b) AFM image of 6μm-sized cross features (c) AFM-Image of 10*10 μm² cross-section of Photoresist Film

XPS STUDIES



High Resolution XPS Data of CAIME-DBTAc Films for C 1s, O 1s, and Sn 3d (a,b,c) before exposure and (d,e,f) after DUV exposure

VERTICAL SHRINKAGE CONTROL



CONCLUSION

- Demonstrated a **dual-component Sn-calixarene hybrid resist system**
- Achieved **good sensitivity improvement** over analogous systems
- Patterning through photolithography supported resist viability
- Platform shows promise for advanced nanopatterning applications.

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REFERENCE

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^aSchool of Chemical Sciences, Indian Institute of Technology Mandi

^bIndian Knowledge System and Mental Health Applications Centre, Indian Institute of Technology Mandi

^cSchool of Computing and Electrical Engineering, Indian Institute of Technology Mandi

^dSpace Applications Centre, Ahmedabad